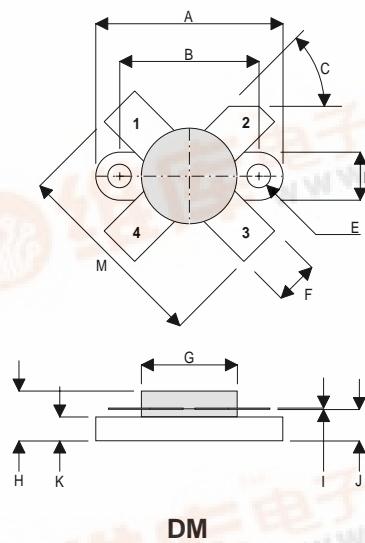




D1003UK

METAL GATE RF SILICON FET

## MECHANICAL DATA



PIN 1	SOURCE	PIN 2	DRAIN
PIN 3	SOURCE	PIN 4	GATE

DIM	mm	Tol.	Inches	Tol.
A	24.76	0.13	0.975	0.005
B	18.42	0.13	0.725	0.005
C	45°	5°	45°	5°
D	6.35	0.13	0.25	0.005
E	3.17 Dia.	0.13	0.125 Dia.	0.005
F	5.71	0.13	0.225	0.005
G	12.7 Dia.	0.13	0.500 Dia.	0.005
H	6.60	REF	0.260	REF
I	0.13	0.02	0.005	0.001
J	4.32	0.13	0.170	0.005
K	3.17	0.13	0.125	0.005
M	26.16	0.25	1.03	0.010

# GOLD METALLISED MULTI-PURPOSE SILICON DMOS RF FET 60W – 28V – 175MHz SINGLE ENDED

## FEATURES

- SIMPLIFIED AMPLIFIER DESIGN
- SUITABLE FOR BROAD BAND APPLICATIONS
- LOW  $C_{rss}$
- SIMPLE BIAS CIRCUITS
- LOW NOISE
- HIGH GAIN – 16 dB MINIMUM

## APPLICATIONS

- HF/VHF COMMUNICATIONS  
from 1 MHz to 175 MHz

ABSOLUTE MAXIMUM RATINGS ( $T_{case} = 25^\circ\text{C}$  unless otherwise stated)

$P_D$	Power Dissipation	117W
$BV_{DSS}$	Drain – Source Breakdown Voltage	70V
$BV_{GSS}$	Gate – Source Breakdown Voltage	$\pm 20\text{V}$
$I_{D(sat)}$	Drain Current	15A
$T_{stg}$	Storage Temperature	-65 to $150^\circ\text{C}$
	Maximum Operating Junction Temperature	200°C



**SEME  
LAB**

**D1003UK**

**ELECTRICAL CHARACTERISTICS** ( $T_{case} = 25^\circ\text{C}$  unless otherwise stated)

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain–Source Breakdown Voltage $V_{GS} = 0$ $I_D = 100\text{mA}$	70			V
$I_{DSS}$	Zero Gate Voltage Drain Current $V_{DS} = 28\text{V}$ $V_{GS} = 0$			1	mA
$I_{GSS}$	Gate Leakage Current $V_{GS} = 20\text{V}$ $V_{DS} = 0$			1	$\mu\text{A}$
$V_{GS(th)}$	Gate Threshold Voltage *	$I_D = 10\text{mA}$	$V_{DS} = V_{GS}$	1	V
$g_{fs}$	Forward Transconductance * $V_{DS} = 10\text{V}$ $I_D = 3\text{A}$	2.4			S
$G_Ps$	Common Source Power Gain $P_O = 60\text{W}$	16			dB
$\eta$	Drain Efficiency $V_{DS} = 28\text{V}$ $I_{DQ} = 0.3\text{A}$	50			%
VSWR	Load Mismatch Tolerance $f = 175\text{MHz}$	20:1			—
$C_{iss}$	Input Capacitance $V_{DS} = 0$ $V_{GS} = -5\text{V}$ $f = 1\text{MHz}$			180	pF
$C_{oss}$	Output Capacitance $V_{DS} = 28\text{V}$ $V_{GS} = 0$ $f = 1\text{MHz}$			90	pF
$C_{rss}$	Reverse Transfer Capacitance $V_{DS} = 28\text{V}$ $V_{GS} = 0$ $f = 1\text{MHz}$			7.5	pF

\* Pulse Test: Pulse Duration = 300  $\mu\text{s}$ , Duty Cycle  $\leq 2\%$

**HAZARDOUS MATERIAL WARNING**

The ceramic portion of the device between leads and metal flange is beryllium oxide. Beryllium oxide dust is highly toxic and care must be taken during handling and mounting to avoid damage to this area.

**THESE DEVICES MUST NEVER BE THROWN AWAY WITH GENERAL INDUSTRIAL OR DOMESTIC WASTE.**

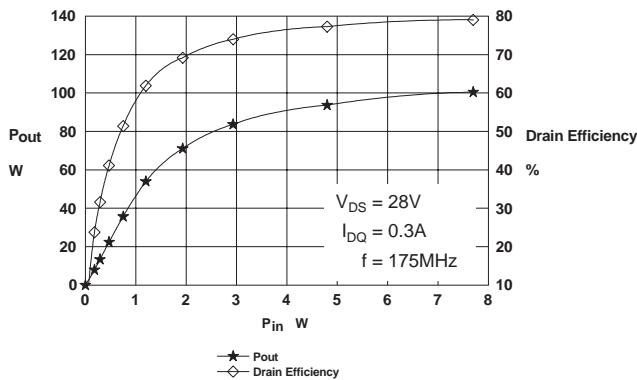
**THERMAL DATA**

$R_{THj-case}$	Thermal Resistance Junction – Case	Max. 1.5°C / W
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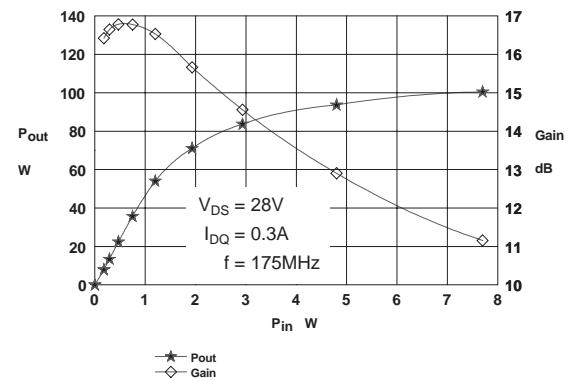


**SEME  
LAB**

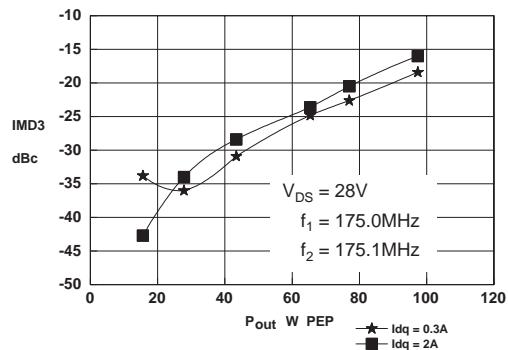
**D1003UK**



**Figure 1 – Power Output and Efficiency vs. Power Input.**



**Figure 2 – Power Output & Gain vs. Power Input.**



**Figure 3 – IMD vs. Output Power.**

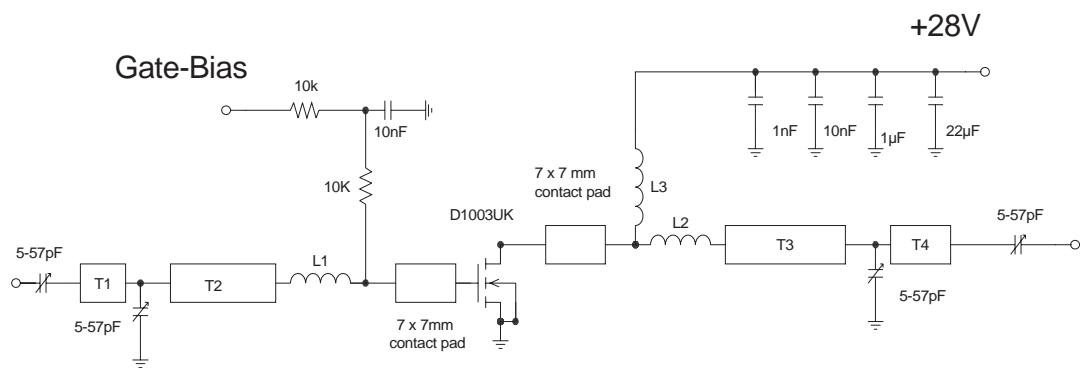
### D1003UK OPTIMUM SOURCE AND LOAD IMPEDANCE

Frequency MHz	Z <sub>S</sub> Ω	Z <sub>L</sub> Ω
175MHz	2.0 - j4.3	3.7 - j4.5

### Typical S Parameters

! V<sub>DS</sub> = 28V, I<sub>DQ</sub> = 0.3A  
# MHZ S MA R 50

Freq MHz	S11		S21		S12		S22	
	mag	ang	mag	ang	mag	ang	mag	ang
70	0.83	-156.8	6.9	59.9	0.018	-16.7	0.65	-137.0
100	0.87	-163.3	4.3	46.9	0.012	-15.5	0.75	-147.2
150	0.91	-171.0	2.3	31.5	0.007	37.1	0.84	-159.7
200	0.93	-177.6	1.4	22.6	0.013	81.0	0.90	-168.8
250	0.95	177.6	0.9	14.3	0.022	86.6	0.93	-175.0
300	0.97	173.6	0.7	10.5	0.032	86.9	0.95	179.5
350	0.96	168.6	0.5	4.0	0.039	80.0	0.96	175.3
400	0.98	165.0	0.4	3.9	0.048	80.0	0.98	172.0
450	0.98	161.9	0.3	2.9	0.053	77.5	0.98	169.8
500	0.97	159.3	0.3	2.1	0.064	74.8	0.97	166.5



## **D1003UK 175MHz TEST FIXTURE**

Substrate 1.6mm PTFE/ glass, Er= 2.5  
 All microstrip lines W= 4.4mm

T1 8mm  
 T2 22mm  
 T3 18mm  
 T4 4.5mm

L1 Hairpin loop 16swg 15.5mm dia.  
 L2 Hairpin loop 16swg 10mm dia.  
 L3 11 turns 18swg enamelled copper wire, 10mm i. d.